

METHOD OF TESTING EMBEDDED MEMORY ARRAY AND EMBEDDED MEMORY TEST CONTROLLER FOR USE THEREWITH

ABSTRACT OF THE DISCLOSURE

5 A memory test controller comprises a test instruction register array for storing
a plurality of test instructions, each register having instruction fields for storing
instruction data specifying operations to be performed on the memory array, a repeat
module for repeating a group of one or more of the test instructions with modified
data, the repeat module including storage means for storing instruction field
10 modification data; and each register of the test instruction register array including an
instruction field for enabling or disabling the repeat module.